

**Search Notes**

Application/Control No.

09/382,371

Examiner

Hai V. Nguyen

Applicant(s)/Patent under  
Reexamination

PHILYAW ET AL.

Art Unit

2142

**SEARCHED**

Class	Subclass	Date	Examiner
705	26	4/29/2006	HN
235	472.03	4/29/2006	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Saerch Updated ( USPGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TBD) (see search history printout)	4/29/2006	HN
ILimited classified search : 705/26; 235/472.03 (see search history printout)	4/29/2006	HN